

An Optimal Tester for k -Linear

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Abstract

A Boolean function $f : \{0, 1\}^n \rightarrow \{0, 1\}$ is k -linear if it returns the sum (over the binary field F_2) of k coordinates of the input. In this paper, we study property testing of the classes k -Linear, the class of all k -linear functions, and k -Linear*, the class $\cup_{j=0}^k j$ -Linear. We give a non-adaptive distribution-free two-sided ϵ -tester for k -Linear that makes

$$O\left(k \log k + \frac{1}{\epsilon}\right)$$

queries. This matches the lower bound known from the literature.

We then give a non-adaptive distribution-free one-sided ϵ -tester for k -Linear* that makes the same number of queries and show that any non-adaptive uniform-distribution one-sided ϵ -tester for k -Linear must make at least $\tilde{\Omega}(k) \log n + \Omega(1/\epsilon)$ queries. The latter bound, almost matches the upper bound $O(k \log n + 1/\epsilon)$ known from the literature. We then show that any adaptive uniform-distribution one-sided ϵ -tester for k -Linear must make at least $\tilde{\Omega}(\sqrt{k}) \log n + \Omega(1/\epsilon)$ queries.

1 Introduction

Property testing of Boolean function was first considered in the seminal works of Blum, Luby and Rubinfeld [9] and Rubinfeld and Sudan [38] and has recently become a very active research area. See for example, [1, 2, 3, 4, 7, 8, 10, 12, 13, 14, 15, 16, 17, 18, 19, 21, 25, 27, 30, 31, 33, 32, 34, 39] and other works referenced in the surveys and books [23, 24, 35, 36].

A Boolean function $f : \{0, 1\}^n \rightarrow \{0, 1\}$ is said to be linear if it returns the sum (over the binary field F_2) of some coordinates of the input, k -linear if it returns the sum of k coordinates, and, k -linear* if it returns the sum of at most k coordinates. The class Linear (resp. k -Linear and k -Linear*) is the classes of all linear functions (resp. all k -linear functions and $\cup_{i=0}^k k$ -Linear). Those classes has been of particular interest to the property testing community [7, 8, 9, 10, 11, 21, 22, 24, 28, 35, 36, 37, 39].

1.1 The Model

Let f and g be two Boolean functions $\{0, 1\}^n \rightarrow \{0, 1\}$ and let \mathcal{D} be a distribution on $\{0, 1\}^n$. We say that f is ϵ -far from g with respect to (w.r.t.) \mathcal{D} if $\Pr_{\mathcal{D}}[f(x) \neq g(x)] \geq \epsilon$ and ϵ -close to g w.r.t. \mathcal{D} if $\Pr_{\mathcal{D}}[f(x) \neq g(x)] \leq \epsilon$.

In the uniform-distribution and distribution-free property testing model, we consider the problem of testing a class of Boolean function C . In the distribution-free testing model (resp. uniform-distribution testing model), the *tester* is a randomized algorithm that has access to a Boolean function $f : \{0, 1\}^n \rightarrow \{0, 1\}$ via a black-box oracle that returns $f(x)$ when a string x is queried. The tester also has access to unknown distribution \mathcal{D} (resp. uniform distribution) via an oracle that returns $x \in \{0, 1\}^n$ chosen randomly according to the distribution \mathcal{D} (resp. according to the uniform distribution). A *distribution-free tester*, [26], (resp. *uniform-distribution tester*) \mathcal{A} for C is an tester that, given as input a distance parameter ϵ and the above two oracles to a Boolean function f ,

1. if $f \in C$ then \mathcal{A} accepts with probability at least $2/3$.
2. if f is ϵ -far from every $g \in C$ w.r.t. \mathcal{D} (resp. uniform distribution) then \mathcal{A} rejects with probability at least $2/3$.

We will also call \mathcal{A} an ϵ -*tester for the class C* or an algorithm for ϵ -*testing C* . We say that \mathcal{A} is *one-sided* if it always accepts when $f \in C$; otherwise, it is called *two-sided* tester. The *query complexity* of \mathcal{A} is the maximum number of queries \mathcal{A} makes on any Boolean function f . If the query complexity is q then we call the tester a q -*query tester* or a tester with *query complexity q* .

In the *adaptive testing* (uniform-distribution or distribution-free) the queries can depend on the answers of the previous queries where in the *non-adaptive testing* all the queries are fixed in advance by the tester.

In this paper we study testers for the classes k -Linear and k -Linear*.

1.2 Prior Results

Throughout this paper we assume that $k < \sqrt{n}$. Blum et al. [9] gave an $O(1/\epsilon)$ -query non-adaptive uniform-distribution one-sided ϵ -tester (called BLR tester) for Linear. Halevy and Kushilevitz, [28], used a self-corrector (an algorithm that computes $g(x)$ from a black box query to f that is ϵ -close to g) to reduce distribution-free testability to uniform-distribution testability. This reduction gives an $O(1/\epsilon)$ -query non-adaptive distribution-free one-sided ϵ -tester for Linear. The reduction can be applied to any subclass of Linear. In particular, any q -query uniform-distribution ϵ -tester for k -Linear (k -Linear*) gives a $O(q)$ -query distribution-free ϵ -tester.

It is well known that if there is a q_1 -query uniform-distribution ϵ -tester for Linear and a q_2 -query uniform-distribution ϵ -tester for the class k -Junta¹ then there is an $O(q_1 + q_2)$ -query uniform-distribution $O(\epsilon)$ -tester for k -Linear*. Since k -Linear = k -Linear* \ $(k - 1)$ -Linear*, if there is a q -query uniform-distribution ϵ -tester for k -Linear* then there is an $O(q)$ -query uniform-distribution two-sided ϵ -tester for k -Linear. Therefore, all the results for testing k -Junta are also true for k -Linear* and k -Linear in the uniform-distribution model.

For lower bounds on the number queries for two-sided uniform-distribution testing k -Linear (see the table in Figure 1): For non-adaptive testers Fisher, et al. [21] gave the lower bound $\Omega(\sqrt{k})$. Goldreich [22], gave the lower bound $\Omega(k)$. In [8], Blais and Kane gave the lower bound $2k - o(k)$. Then in [7], Blais et al. gave the lower bound $\Omega(k \log k)$. For adaptive testers, Goldreich [22], gave the lower bound $\Omega(\sqrt{k})$. Then Blais et al. [7] gave the lower bound $\Omega(k)$ and in [8], Blais and Kane

¹The class of boolean functions that depends on at most k coordinates

gave the lower bound $k - o(k)$. Then in [39], Saglam gave the lower bound $\Omega(k \log k)$. This bound with the trivial $\Omega(1/\epsilon)$ lower bound gives the lower bound

$$\Omega\left(k \log k + \frac{1}{\epsilon}\right) \tag{1}$$

for the query complexity of any adaptive uniform-distribution (and distribution-free) two-sided testers.

For upper bounds for uniform-distribution two-sided ϵ -testing k -Linear, Fisher, et al. [21] gave the first adaptive tester that makes $O(k^2/\epsilon)$ queries. In [11], Buhrman et al. gave a non-adaptive tester that makes $O(k \log k)$ queries for any constant ϵ . As is mentioned above, testing k -Linear can be done by first testing if the function is k -Junta and then testing if it is Linear. Therefore, using Blais [5, 6] adaptive and non-adaptive testers for k -Junta we get adaptive and non-adaptive uniform-distribution testers for k -Linear that makes $O(k \log k + k/\epsilon)$ and $\tilde{O}(k^{1.5}/\epsilon)$ queries, respectively.

For upper bounds for two-sided distribution-free testing k -Linear, as is mentioned above, from Halevy et al. reduction in [28], an adaptive and non-adaptive distribution-free ϵ -tester can be constructed from adaptive and non-adaptive uniform-distribution ϵ -testers. This gives an adaptive and non-adaptive distribution-free two-sided testers for k -Linear that makes $O(k \log k + k/\epsilon)$ and $\tilde{O}(k^{1.5}/\epsilon)$ queries, respectively. See the table in Figure 1.

1.3 Our Results

In this paper we prove

Theorem 1. *For any $\epsilon > 0$, there is a polynomial time non-adaptive distribution-free one-sided ϵ -tester for k -Linear* that makes*

$$O\left(k \log k + \frac{1}{\epsilon}\right)$$

queries.

By the reduction from k -Linear to k -Linear*, we get

Theorem 2. *For any $\epsilon > 0$, there is a polynomial time non-adaptive distribution-free two-sided ϵ -tester for k -Linear that makes*

$$O\left(k \log k + \frac{1}{\epsilon}\right)$$

queries.

For one-sided testers for k -Linear we prove

Theorem 3. *Any non-adaptive uniform-distribution one-sided ϵ -tester for k -Linear must make at least $\tilde{\Omega}(k) \log n + \Omega(1/\epsilon)$ queries.*

This almost matches the upper bound $O(k \log n + 1/\epsilon)$ that follows from the reduction of Goldreich et. al [26] and the non-adaptive deterministic exact learning algorithm of Hofmeister [29] that learns k -Linear with $O(k \log n)$ queries.

For adaptive testers we prove

Theorem 4. *Any adaptive uniform-distribution one-sided ϵ -tester for k -Linear must make at least $\tilde{\Omega}(\sqrt{k}) \log n + \Omega(1/\epsilon)$ queries.*

The table in 1 summarizes all the results in the literature and our results for the class k -Linear.

Upper/ Lower	One-Sided/ Two-Sided	Adaptive/ Non-Adap.	Uniform/ Dist. Free	Result O/Ω	Reference
Upper	Two-Sided	Adaptive	Uniform	k^2/ϵ	[21]
Upper	Two-Sided	Adaptive	Uniform	$k \log k + k/\epsilon$	[6]
Upper	Two-Sided	Adaptive	Dist. Free	$k \log k + k/\epsilon$	[28]
Upper	Two-Sided	Non-Adap.	Uniform	$k \log k$ (ϵ Const.)	[11]
Upper	Two-Sided	Non-Adap.	Uniform	$k^{1.5}/\epsilon$	[5]
Upper	Two-Sided	Non-Adap.	Dist. Free	$k^{1.5}/\epsilon$	[28]
Upper	Two-Sided	Non-Adap.	Dist. Free	$k \log k + 1/\epsilon$	Ours
Lower	Two-Sided	Non-Adap.	Uniform	$1/\epsilon$	Trivial
Lower	Two-Sided	Non-Adap.	Uniform	$\sqrt{k} + 1/\epsilon$	[21]
Lower	Two-Sided	Non-Adap.	Uniform	$k + 1/\epsilon$	[22]
Lower	Two-Sided	Non-Adap.	Uniform	$k \log k + 1/\epsilon$	[7]
Lower	Two-Sided	Adaptive	Uniform	$\sqrt{k} + 1/\epsilon$	[22]
Lower	Two-Sided	Adaptive	Uniform	$k + 1/\epsilon$	[7, 8]
Lower	Two-Sided	Adaptive	Uniform	$k \log k + 1/\epsilon$	[39]
Upper	One-Sided	Non-Adaptive	Dist. Free	$k \log n + 1/\epsilon$	[26]
Lower	One-Sided	Non-Adaptive	Uniform	$\tilde{\Omega}(k) \log n + 1/\epsilon$	Ours
Lower	One-Sided	Adaptive	Uniform	$\tilde{\Omega}(\sqrt{k}) \log n + 1/\epsilon$	Ours

Figure 1: A table of results for the testability of the class k -Linear.

2 Overview of the Testers and Lower Bounds

In this section we give overview of the techniques used for proving the results in this paper.

2.1 One-sided Tester for k -Linear*

The tester for k -Linear* first runs the tester BLR of Blum et al. [9] to test if the function f is ϵ' -close to Linear w.r.t. the uniform distribution, where $\epsilon' = \Theta(1/(k \log k))$. BLR is one-sided tester and therefore, if f is k -linear then BRG accepts with probability 1. If f is ϵ' -far from Linear w.r.t. the uniform distribution then, with probability at least $2/3$, BLR rejects. Therefore, if the tester BLR accepts, we may assume that f is ϵ' -close to Linear w.r.t. the uniform distribution. Let $g \in \text{Linear}$ be the function that is ϵ' -close to f . If f is k -linear* then $f = g$. This is because $\epsilon' < 1/8$ and the distance (w.r.t. the uniform distribution) between every two linear functions is $1/2$. BLR makes $O(1/\epsilon') = O(k \log k)$ queries.

In the second stage, the tester tests if g (not f) is k -linear*. Let us assume for now that we can query g in every string. Since $g \in \text{Linear}$, we need to distinguish between functions in k -Linear* and functions in $\text{Linear} \setminus k$ -Linear*. We do that with two tests. We first test if $g \in 8k$ -Linear* and then test if it is in k -Linear* assuming that it is in $8k$ -Linear*. In the first test, the tester “throws”, uniformly at random, the variables of g into $16k$ bins and tests if there is more than k non-empty bins. If g is k -linear* then the number of non-empty bins is always less than k . If it is k' -linear for some $k' > 8k$ then with high probability (w.h.p.) the number of non-empty bins is greater than k . Notice that if f is k -linear* then the test always accepts and therefore it is one-sided. This tests

makes $O(k)$ queries to g .

The second test is testing if g is in k -Linear* assuming that it is in $8k$ -Linear*. This is done by projecting the variables of g into $r = O(k^2)$ coordinates uniformly at random and learning (finding exactly) the projected function using the non-adaptive deterministic Hofmeister's algorithm, [29], that makes $O(k \log r) = O(k \log k)$ queries. Since $g \in 8k$ -Linear*, w.h.p., the relevant coordinates of the function are projected to different coordinates, and therefore, w.h.p., the learning gives a linear function that has exactly the same number of relevant coordinates as g . The tester accepts if the number of relevant coordinates in the projected function is at most k . If $g \in k$ -Linear*, then the projected function is in k -Linear* with probability 1 and therefore this test is one-sided. This test makes $O(k \log k)$ queries.

We assumed that we can query g . We now show how to query g in $O(k \log k)$ strings so we can apply the above two tests. For this, the tester uses self-corrector, [9]. To compute $g(z)$, the self-corrector chooses a uniform random string $a \in \{0, 1\}^n$ and computes $f(z + a) + f(a)$. Since f is $O(1/(k \log k))$ -close to g w.r.t. the uniform distribution, we have that for any string $z \in \{0, 1\}^n$ and an $a \in \{0, 1\}^n$ chosen uniformly at random, with probability at least $1 - O(1/(k \log k))$, $f(z + a) + f(a) = g(z + a) + g(a) = g(z)$. Therefore, w.h.p., the self-corrector computes correctly the values of g in $O(k \log k)$ strings. If $f \in k$ -Linear then $g = f$ and $f(z + a) + f(z) = f(z) = g(z)$, i.e., the self-corrector gives the value of g with probability 1. This shows that the above two tests are one-sided.

Now, if f is k -linear* then $f = g$. If f is ϵ -far from every function in k -Linear* w.r.t. \mathcal{D} then it is ϵ -far from g w.r.t. \mathcal{D} .

In the final stage the tester tests whether f is equal to g or ϵ -far from g w.r.t. \mathcal{D} . Here again the tester uses self-corrector. It asks for a sample $\{(z^{(i)}, f(z_i)) | i \in [t]\}$ according to the distribution \mathcal{D} of size $t = O(1/\epsilon)$ and tests if $f(z^{(i)}) = f(z^{(i)} + a^{(i)}) + f(a^{(i)})$ for every $i \in [t]$, where $a^{(i)}$ are i.i.d. uniform random strings. If $f(z^{(i)}) = f(z^{(i)} + a^{(i)}) + f(a^{(i)})$ for all i then it accepts, otherwise, it rejects. If f is k -linear then $f(z^{(i)}) = f(z^{(i)} + a^{(i)}) + f(a^{(i)})$ for all i and the tester accepts with probability 1. Now suppose f is ϵ -far from g w.r.t. \mathcal{D} . Since f is ϵ' -close to g w.r.t. the uniform distribution and $\epsilon' \leq 1/8$ we have that, with probability at least $7/8$, $f(z^{(i)} + a^{(i)}) + f(a^{(i)}) = g(z^{(i)} + a^{(i)}) + g(a^{(i)}) = g(z^{(i)})$. Therefore, assuming the latter happens, then, with probability at least $1 - \epsilon$ we have $f(z^{(i)}) \neq g(z^{(i)}) = f(z^{(i)} + a^{(i)}) + f(a^{(i)})$. Thus, w.h.p, there is i such that $f(z^{(i)}) \neq f(z^{(i)} + a^{(i)}) + f(a^{(i)})$ and the tester rejects. This stage is one-sided and makes $O(1/\epsilon)$ queries.

2.2 Two-sided Testers for k -Linear

As we mentioned in the introduction, the one-sided q -query uniform-distribution ϵ -tester for k -Linear* gives a two-sided uniform-distribution $O(q)$ -query ϵ -tester for k -Linear. This is because, in the uniform distribution, the linear functions are $1/2$ -far from each other and therefore, for any $\epsilon < 1/4$, if f is ϵ -close to a k -linear function g then it is $(1/2 - \epsilon)$ -far from $(k - 1)$ -Linear*. This is not true for any distribution \mathcal{D} , and therefore, cannot be applied here.

The algorithm in the previous subsection can be changed to a two-sided tester for k -Linear as follows. The only part that should be changed is the test that g is in k -Linear* assuming that it is in $8k$ -Linear*. We replace it with a test that g is in k -Linear assuming that it is in $8k$ -Linear*. The tester rejects if the number of relevant coordinates in the function that is learned is not *equal* to k . This time the test is two-sided. The reason is that the projection to $O(k^2)$ variables does not guarantee (with probability 1) that all the variables of f are projected to different variables.

Therefore, it may happen that f is k -linear and the projection gives a $(k - 1)$ -linear* function.

2.3 The Lower Bound for One-sided Testers

We first show the result for non-adaptive testers. Suppose there is a one-sided non-adaptive uniform distribution $1/8$ -tester $A(s, f)$ for k -Linear that makes q queries, where s is the random seed of the tester and f is the function that is tested. The algorithm has access to f through a black box queries.

Consider the set of linear functions $C = \{g^{(0)}\} \cup \{g^{(\ell)} = x_n + \dots + x_{n-\ell+1} \mid \ell = 1, \dots, k - 1\} \subseteq (k - 1)$ -Linear* where $g^{(0)} = 0$. Any k -linear function is $1/2$ -far from every function in C w.r.t. the uniform distribution. Therefore, using the tester A , with probability at least $2/3$, we can distinguish between any k -linear and any function in C . By running the tester A $O(\log k)$ times, and accept if and only if all accept, we get a tester A' that asks $O(q \log k)$ queries and satisfies

1. If $f \in k$ -Linear then with probability 1, $A'(s, f)$ accepts.
2. If $f \in C$ then, with probability at least $1 - 1/(2k)$, $A'(s, f)$ rejects.

By an averaging argument (i.e., fixing coins for A') and since $|C| = k$, there exists a deterministic non-adaptive algorithm B that makes $q' = O(q \log k)$ queries such that

1. If $f \in k$ -Linear then $B(f)$ accepts.
2. If $f = C$ then $B(f)$ rejects.

Let $a^{(i)}$, $i = 1, \dots, q'$ be the queries that B makes. Let M be a $q' \times n$ binary matrix where the i -th row of M is $a^{(i)}$ and $x^f \in \{0, 1\}^n$ where $x_i^f = 1$ if i is a relevant coordinate in f . Then the vector of answers to the queries of $B(f)$ is Mx^f . If $Mx^f = Mx^g$ for some $g \in C$, that is, the answers of the queries to f are the same as the answer of the queries to g , then $B(f)$ rejects. Therefore, for every $f \in k$ -Linear and every $g \in C$ we have $Mx^f \neq Mx^g$. Now since $\{x^f \mid f \in k\text{-Linear}\}$ is the set of all strings of weight k , the sum (over the field F_2) of every k columns of M is not equal to 0 and not equal to the sum of the last ℓ columns of M , for all $\ell = 1, \dots, k - 1$. In particular, if M_i is the i th column of M , for every $i_1, \dots, i_{k-\ell} \leq n - k + 1$, $M_{i_1} + \dots + M_{i_{k-\ell}} + M_{n-\ell+1} + \dots + M_n \neq M_{n-\ell+1} + \dots + M_n$ and therefore $M_{i_1} + \dots + M_{i_{k-\ell}} \neq 0$. That is, the sum of every less or equal $k - 1$ columns of the first $n - k + 1$ columns of M is not equal to zero. We then show (via Hamming's bound in coding theory) that such matrix has at least $q' = \Omega(k \log n)$ rows. This implies that $q = \Omega((k/\log k) \log n)$. See more details in Subsection 4.1.

For the lower bound for adaptive testers we take $C = \{g^{(\ell)}\}$ for some $\ell \in \{0, 1, \dots, k - 1\}$ and get a $q \times n$ matrix M that the sum of every $k - \ell$ columns of M is not zero. We then show, that there exists $\ell \leq k - 1$ where such a matrix must have at least $q = \tilde{\Omega}(\sqrt{k} \log n)$ rows. See more details in Subsections 4.2 and 4.3.

3 The Testers for k -Linear* and k -Linear

In this section we give the non-adaptive distribution-free one-sided tester for k -Linear* and the non-adaptive distribution-free two-sided tester for k -Linear.

3.1 Notations

In this subsection, we give some notations that we use throughout the paper.

Denote $[n] = \{1, 2, \dots, n\}$. For $S \subseteq [n]$ and $x = (x_1, \dots, x_n)$. For $X \subseteq [n]$ we denote by $\{0, 1\}^X$ the set of all binary strings of length $|X|$ with coordinates indexed by $i \in X$. For $x \in \{0, 1\}^n$ and $X \subseteq [n]$ we write $x_X \in \{0, 1\}^X$ to denote the projection of x over coordinates in X . We denote by 1_X and 0_X the all-one and all-zero strings in $\{0, 1\}^X$, respectively. For a variable x_i and a set X , we denote by $(x_i)_X$ the string x' over coordinates in X where for every $j \in X$, $x'_j = x_i$. For $X_1, X_2 \subseteq [n]$ where $X_1 \cap X_2 = \emptyset$ and $x \in \{0, 1\}^{X_1}, y \in \{0, 1\}^{X_2}$ we write $x \circ y$ to denote their concatenation, i.e., the string in $\{0, 1\}^{X_1 \cup X_2}$ that agrees with x over coordinates in X_1 and agrees with y over coordinates in X_2 . For $X \subseteq [n]$ we denote $\overline{X} = [n] \setminus X = \{x \in [n] \mid x \notin X\}$.

For example, if $n = 7$, $X_1 = \{1, 3, 5\}$, $X_2 = \{2, 7\}$, y_2 is a variable and $z = (z_1, z_2, z_3, z_4, z_5, z_6, z_7) \in \{0, 1\}^7$ then $(y_2)_{X_1} \circ z_{X_2} \circ 0_{\overline{X_1 \cup X_2}} = (y_2, z_2, y_2, 0, y_2, 0, z_7)$.

3.2 The Tester

Consider the tester **Test-Linear** $_k^*$ for k -Linear * in Figure 2. The tester uses three procedures. The first is **Self-corrector** that for an input $x \in \{0, 1\}^n$ chooses a uniform random $z \in \{0, 1\}^n$ and returns $f(x+z) + f(z)$. The procedure **BLR** that is a non-adaptive uniform-distribution one-sided ϵ -tester for Linear. BLR makes c_1/ϵ queries for some constant c_1 , [9]. The third procedure is **Hoffmeister's Algorithm** (N, K) , a deterministic non-adaptive algorithm that exactly learns K -Linear * over N coordinates from black box queries. Hoffmeister's Algorithm makes $c_2 K \log N$ queries for some constant c_2 , [29].

To test k -Linear we use the same tester but change step 11 to:

(11) If the output is not in k -Linear then reject

We call this tester **Test-Linear** $_k$.

3.3 Correctness of the Tester

In this section we prove

Theorem 5. **Test-Linear** $_k$ is a non-adaptive distribution-free two-sided ϵ -tester for k -Linear that makes

$$O\left(k \log k + \frac{1}{\epsilon}\right)$$

queries.

Theorem 6. **Test-Linear** $_k^*$ is a non-adaptive distribution-free one-sided ϵ -tester for k -Linear * that makes

$$O\left(k \log k + \frac{1}{\epsilon}\right)$$

queries.

Proof. Since there is no stage in the tester that uses the answers of the queries asked in previous ones, the tester is non-adaptive.

In Stage 1 the tester makes $O(1/\epsilon') = O(k \log k)$ queries. In stage 2.1, $O(k)$ queries. In stage 2.2, $O(k \log r) = O(k \log k)$ queries and in stage 3, $O(1/\epsilon)$ queries. Therefore, the query complexity of the tester is $O(k \log k + 1/\epsilon)$.

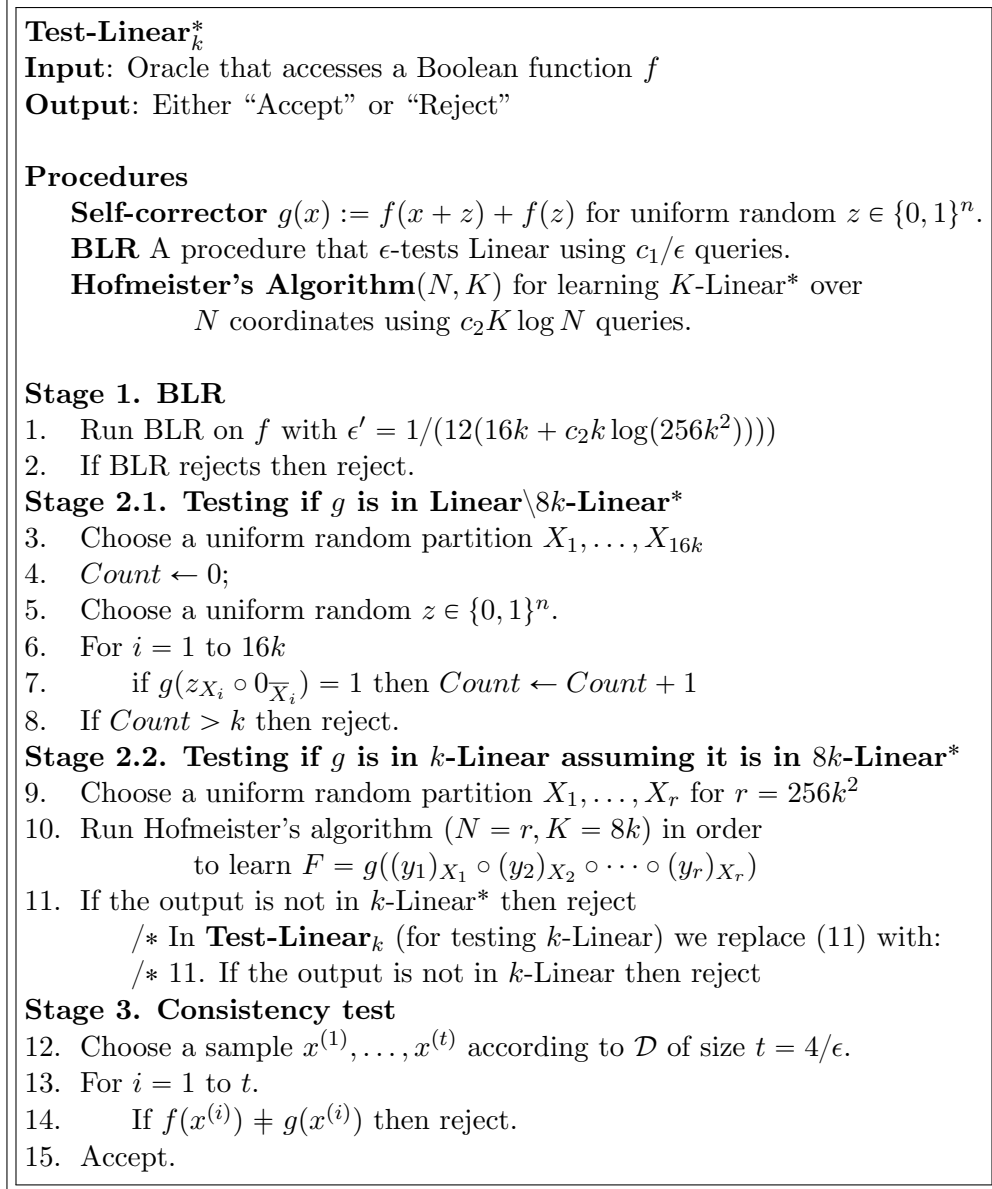


Figure 2: An optimal two-sided tester for k -Linear.

We will assume that $k \geq 12$. For $k < 12$, (see the introduction and Table 1) the non-adaptive tester of k -Junta with the BLR tester and the self-corrector gives a non-adaptive testers that makes $O(1/\epsilon) = O(k \log k + 1/\epsilon)$ queries.

Completeness: We first show the completeness for **Test-Linear_k** that tests k -Linear. Suppose $f \in k$ -Linear. Then for every x we have $g(x) = f(x + z) + f(z) = f(x) + f(z) + f(z) = f(x)$. Therefore, $g = f$. In stage 1, BLR is one-sided and therefore it does not reject. In stage 2.1, since X_1, \dots, X_{16k} are pairwise disjoint, the number of functions $g(x_{X_i} \circ 0_{\overline{X_i}})$, $i = 1, 2, \dots, 16k$, that are not identically zero is at most k and therefore stage 2.1 does not reject. In stage 2.2, with

probability at least $1 - \binom{k}{2}/(256k^2) \geq 2/3$, the relevant coordinates of f fall into different X_i and then $F = g((y_1)_{X_1} \circ (y_2)_{X_2} \circ \dots \circ (y_r)_{X_r}) = f((y_1)_{X_1} \circ (y_2)_{X_2} \circ \dots \circ (y_r)_{X_r})$ is k -linear. Then, Hofmeister's algorithm returns a k -linear function. Therefore, with probability at least $2/3$ the tester does not reject. Stage 3 does not reject since $f = g$.

Now for the tester **Test-Linear** $_k^*$, in stage 2.2, with probability 1 the function F is in k -Linear * . In fact, if t relevant coordinates falls into the set X_i then the coordinate i (that correspond to the variable y_i) will be relevant in F if and only if t is odd. Therefore, the tester does not reject.

Notice that **Test-Linear** $_k^*$ is one-sided and **Test-Linear** $_k$ is two-sided.

Soundness: We prove the soundness for **Test-Linear** $_k$. The same proof also works for **Test-Linear** $_k^*$. Suppose f is ϵ -far from k -Linear w.r.t. the distribution \mathcal{D} . We have four cases

Case 1 : f is ϵ' -far from Linear w.r.t. the uniform distribution.

Case 2 : f is ϵ' -close to $g \in \text{Linear}$ and g is in $\text{Linear} \setminus 8k\text{-Linear}^*$.

Case 3 : f is ϵ' -close to $g \in \text{Linear}$ and g is in $8k\text{-Linear}^* \setminus k\text{-Linear}$.

Case 4 : f is ϵ' -close to $g \in \text{Linear}$, g is in $k\text{-Linear}$ and f is ϵ -far from $k\text{-Linear}$ w.r.t. \mathcal{D} .

For Case 1, if f is ϵ' -far from Linear then, in stage 1, BLR rejects with probability $2/3$.

For Cases 2 and 3, since f is ϵ' -close to g , for any fixed $x \in \{0, 1\}^n$ with probability at least $1 - 2\epsilon'$ (over a uniform random z), $f(x+z) + f(z) = g(x+z) + g(z) = g(x)$. Since stages 2.1 and 2.2 makes $(16k + c_2k \log r)$ queries (to g), with probability at least $1 - (16k + c_2k \log r)2\epsilon' \geq 5/6$, $g(x)$ is computed correctly for all the queries in stages 2.1 and 2.2.

For Case 2, consider stage 2.1 of the tester. If g is in $\text{Linear} \setminus 8k\text{-Linear}^*$ then g has more than $8k$ relevant coordinates. The probability that less than or equal to $4k$ of X_1, \dots, X_{16k} contains relevant coordinates of g is at most

$$\binom{16k}{4k} \frac{1}{4^{8k}} \leq \left(\frac{e16k}{4k} \right)^{4k} \frac{1}{4^{8k}} \leq \frac{1}{12}.$$

If X_i contains the relevant coordinates i_1, \dots, i_ℓ then $g(x_{X_i} \circ 0_{\overline{X_i}}) = x_{i_1} + \dots + x_{i_\ell}$ and therefore, for a uniform random $z \in \{0, 1\}^n$, with probability at least $1/2$, $g(z_{X_i} \circ 0_{\overline{X_i}}) = 1$. Therefore, if at least $4k$ of X_1, \dots, X_{16k} contains relevant coordinates then, by Chernoff bound, with probability at least $1 - e^{-k/4} \geq 11/12$, the counter "*Count*" is greater than k . Therefore, for Case 2, if g is in $\text{Linear} \setminus 8k\text{-Linear}^*$ then, with probability at least $1 - (1/6 + 1/12 + 1/12) = 2/3$, the tester rejects.

For Case 3, consider stage 2.2. If g is in $8k\text{-Linear}^* \setminus k\text{-Linear}$ then g has at most $8k$ relevant coordinates. Then with probability at least $1 - \binom{8k}{2}/(256k^2) \geq 5/6$, the relevant coordinates of g fall into different X_i and then Hofmeister's algorithm returns a linear function with the same number of relevant coordinates as g . Therefore stage 2.2 rejects with probability at least $2/3$.

For Case 4, if g is in $k\text{-Linear}$ and f is ϵ -far from $k\text{-Linear}$ w.r.t. \mathcal{D} , then f is ϵ -far from g w.r.t. \mathcal{D} . Then for uniform random z and $x \sim \mathcal{D}$,

$$\begin{aligned} \Pr_{\mathcal{D}, z}[f(x) \neq g(x)] &\geq \Pr_{\mathcal{D}, z}[f(x) \neq g(x) | g(x) = f(x+z) + f(z)] \Pr_{\mathcal{D}, z}[g(x) = f(x+z) + f(z)] \\ &= \Pr_{\mathcal{D}}[f(x) \neq g(x)] \Pr_z[g(x) = f(x+z) + f(z)] \\ &\geq \epsilon(1 - \epsilon') \geq \epsilon/2. \end{aligned}$$

Therefore, with probability at most $(1 - \epsilon/2)^t = (1 - \epsilon/2)^{4/\epsilon} \leq 1/3$, stage 3 does not reject. \square

4 Lower Bound

In this section we prove

Theorem 7. *Any non-adaptive uniform-distribution one-sided 1/8-tester for k -Linear must make at least $\tilde{\Omega}(k \log n)$ queries.*

Theorem 8. *Any adaptive uniform-distribution one-sided 1/8-tester for k -Linear must make at least $\tilde{\Omega}(\sqrt{k} \log n)$ queries.*

4.1 Lower Bound for Non-Adaptive Testers

We first show the result for non-adaptive testers.

Suppose there is a non-adaptive uniform-distribution one-sided 1/8-tester $A(s, f)$ for k -Linear that makes q queries, where s is the random seed of the tester and f is the function that is tested. The algorithm has access to f through a black box queries.

Consider the set of linear functions $C = \{g^{(0)}\} \cup \{g^{(\ell)} = x_n + \dots + x_{n-\ell+1} \mid \ell = 1, \dots, k-1\} \subseteq (k-1)\text{-Linear}^*$ where $g^{(0)} = 0$. Any k -linear function is 1/2-far from every function in C w.r.t. the uniform distribution. Therefore, using the tester A , with probability at least 2/3, A can distinguish between any k -linear function and functions in C . We boost the success probability to $1 - 1/(2k)$ by running A , $\log(2k)/\log 3$ times, and accept if and only if all accept. We get a tester A' that asks $O(q \log k)$ queries and satisfies

1. If $f \in k\text{-Linear}$ then with probability 1, $A'(s, f)$ accepts.
2. If $f \in C$ then, with probability at least $1 - 1/(2k)$, $A'(s, f)$ rejects.

Therefore, the probability that for a uniform random s , $A'(s, f)$ accepts for some $f \in C$ is at most 1/2. Thus, there is a seed s_0 such that $A'(s_0, f)$ rejects for all $f \in C$ (and accept for all $f \in k\text{-Linear}$). This implies that there exists a deterministic non-adaptive algorithm $B(= A'(s_0, *))$ that makes $q' = O(q \log k)$ queries such that

1. If $f \in k\text{-Linear}$ then $B(f)$ accepts.
2. If $f \in C$ then $B(f)$ rejects.

Let $a^{(i)}$, $i = 1, \dots, q'$ be the queries that B makes. Let M be a $q' \times n$ binary matrix that its i -th row is $a^{(i)}$. Let $x^f \in \{0, 1\}^n$ where $x_i^f = 1$ iff i is relevant coordinate in f . Then the vector of answers to the queries of $B(f)$ is Mx^f . If $Mx^f = Mx^g$ for some $g \in C$, that is, the answers of the queries to f are the same as the answers of the queries to g , then $B(f)$ rejects. Therefore, for every $f \in k\text{-Linear}$ and every $g \in C$ we have $Mx^f \neq Mx^g$. Now since $\{x^f \mid f \in k\text{-Linear}\}$ is the set of all strings of weight k , the sum (over the field F_2) of every k columns of M is not equal to 0 (zero string) and not equal to the sum of the last ℓ columns of M , for all $\ell = 1, \dots, k-1$. In particular, if M_i is the i th column of M , for every $i_1, \dots, i_{k-\ell} \leq n-k+1$, $M_{i_1} + \dots + M_{i_{k-\ell}} + M_{n-\ell+1} + \dots + M_n \neq M_{n-\ell+1} + \dots + M_n$ and therefore $M_{i_1} + \dots + M_{i_{k-\ell}} \neq 0$. That is, the sum of every less or equal k columns of the first $n-k+1$ columns of M is not equal to zero. We then show in Lemma 10 that such matrix has at least $q' = \Omega(k \log n)$ rows. This implies that $q = \Omega((k/\log k) \log n)$.

Let $\pi(n, k)$ be the minimum integer q such that there exists a $q \times n$ matrix over F_2 that the sum of any of its less than or equal k columns is not 0. We have proved

Lemma 9. *Any non-adaptive uniform-distribution one-sided $1/8$ -tester for k -Linear must make at least $\Omega(\pi(n - k + 1, k)/\log k)$ queries.*

Now to show that $\Omega(\pi(n - k + 1, k)/\log k) = \Omega(k \log n)$ we prove the following result. This lemma follows from Hamming's bound in coding theory. We give the proof for completeness

Lemma 10. (*Hamming's Bound*) *We have*

$$\pi(n, k) \geq \log \sum_{i=0}^{\lfloor \frac{k}{2} \rfloor} \binom{n}{i} = \Omega(k \log(n/k)).$$

Proof. Let M be a $\pi(n, k) \times n$ matrix over F_2 that the sum of any of its less than or equal k columns is not 0. Let $m = \lfloor k/2 \rfloor$ and $S = \{M_{i_1} + \dots + M_{i_t} \mid t \leq m \text{ and } 1 \leq i_1 < \dots < i_t \leq n\} \subseteq \{0, 1\}^{\pi(n, k)}$ be a multiset. The strings in S are distinct because, if for the contrary, we have two strings in S that satisfies $M_{i_1} + \dots + M_{i_t} = M_{j_1} + \dots + M_{j_{t'}}$ then $M_{i_1} + \dots + M_{i_t} + M_{j_1} + \dots + M_{j_{t'}} = 0$ (equal columns are cancelled) and $t + t' \leq k$, which is a contradiction. Therefore, $2^{\pi(n, k)} \geq |S| = \sum_{i=0}^m \binom{n}{i}$ and $\pi(n, k) \geq \log |S|$. \square

4.2 Lower Bound for Adaptive Testers

For the lower bound for adaptive testers we take $C = \{g^{(\ell)}\}$ for some $\ell \in \{0, 1, \dots, k - 1\}$ and get an adaptive algorithm A that makes q queries and satisfies

1. If $f \in k$ -Linear then with probability 1, $A(s, f)$ accepts.
2. If $f = g^{(\ell)}$ then, with probability at least $2/3$, $A(s, f)$ rejects.

This implies that there exists a deterministic adaptive algorithm $B = A(s_0, *)$ that makes q queries such that

1. If $f \in k$ -Linear then $B(f)$ accepts.
2. If $f = g^{(\ell)}$ then $B(f)$ rejects.

Then, by the same argument as in the case of non-adaptive tester, we get a $q \times n$ matrix M that the sum of every $k - \ell$ columns of the first $n - \ell$ columns of M is not zero. Let $\Pi(n, k)$ be the minimum integer q such that there exists a $q \times n$ matrix over F_2 that the sum of any of its k columns is not 0. Then, we have proved that

Lemma 11. *Any adaptive uniform-distribution one-sided $1/8$ -tester for k -Linear must make at least $\Omega(\max_{1 \leq \ell \leq k} \Pi(n - k, \ell))$ queries.*

In the next subsection, we show that there exists $1 \leq \ell \leq k$ such that $\Pi(n, \ell) = \tilde{\Omega}(\sqrt{k} \log n)$.

4.3 A Lower Bound for Π

In this section we prove

Lemma 12. *We have $\max_{1 \leq \ell \leq k} \Pi(n, \ell) = \tilde{\Omega}(\sqrt{k} \log n)$.*

The idea of the proof is the following. For a set of integers L an L -good matrix M is a matrix that for every $\ell \in L$ the sum of every ℓ columns of M is not zero. A k -good matrix is a $\{k\}$ -good matrix. We say that the matrix M is *almost L -good* if there is a “small” number ($poly(k)$) of columns of M that can be removed to get an L -good matrix. The concatenation $M_1 \circ M_2$ (the matrix that contains the rows of both matrices) of almost L_1 -good matrix M_1 with an almost L_2 -good matrix M_2 is an almost $L_1 \cup L_2$ -good matrix.

Let $K = \lfloor \sqrt{k}/(2 \log k) \rfloor$ and $[K] = \{1, 2, \dots, K\}$. The idea of the proof is to construct an almost $[K]$ -good matrix M by concatenating $t = O(\log k)$ matrices $M_1 \circ M_2 \circ \dots \circ M_t$ where M_i is k_i -good ($\Pi(n, k_i) \times n$)-matrices for some $k_i \leq k$. Then after removing small number ($poly(k)$) columns of M we get a $[K]$ -good matrix M with $\sum_{i=1}^t \Pi(n, k_i)$ rows and $n - poly(k)$ columns. By Hamming’s bound, Lemma 10, M contains at least $\Omega(K \log n)$ rows. Therefore, $\sum_{i=1}^t \Pi(n, k_i) = \Omega(K \log n)$. So there is i such that $\Pi(n, k_i) = \Omega(K \log n / \log k) = \Omega(\sqrt{k} \log n / \log^2 k) = \tilde{\Omega}(\sqrt{k} \log n)$.

We now give more intuition to how to construct an almost $[K]$ -good matrix from k_i -good matrices. Denote by $\mathbb{N}_d = \{i : d \nmid i\} \cap [K]$. Let $k = k_1$. We first show that if M_1 is k_1 -good matrix then there exists a set of integers $L_1 \subseteq [K]$ such that M_1 is almost L_1 -good matrix and $d_1 := \gcd([K] \setminus L_1) \nmid k_1$. The intuition is that if, for the contrary, there are many pairwise disjoint sets of columns that sum to 0 that the great common divisor of their sizes divides k_1 , then the union of some of them gives k_1 -set of columns that sum to 0 and then we get a contradiction. Therefore $d_1 \neq 1$, $L_1 \supseteq \mathbb{N}_{d_1}$ and M_1 is almost \mathbb{N}_{d_1} -good. We then take $k_2 := d_1 \lfloor k/d_1 \rfloor$ and a k_2 -good $\Pi(n, k_2) \times n$ matrix M_2 . Then, as before, M_2 is almost \mathbb{N}_{d_2} -good matrix with $d_2 \nmid k_2$. Therefore, $d_2 \nmid d_1$. Now the concatenation of both matrices $M_1 \circ M_2$ is almost $\mathbb{N}_{d_1} \cup \mathbb{N}_{d_2} = \mathbb{N}_{\text{lcm}(d_1, d_2)}$. Since $d_2 \nmid d_1$ we must have $d'_2 := \text{lcm}(d_1, d_2) \geq 2d_1$. We then take $k_3 = d'_2 \lfloor k/d'_2 \rfloor$ and a k_3 -good $\Pi(n, k_3) \times n$ matrix M_3 and concatenate it with $M_1 \circ M_2$ to get an almost $\mathbb{N}_{\text{lcm}(d_1, d_2, d_3)}$ -good matrix with $\text{lcm}(d_1, d_2, d_3) \geq 2d'_2 = 2 \text{lcm}(d_1, d_2) \geq 4d_1$. After, $t = O(\log k)$ iterations, we get a $(\sum_{i=1}^t \Pi(n, k_i)) \times n$ matrix $M = M_1 \circ M_2 \circ \dots \circ M_t$ that is almost \mathbb{N}_d -good for some $d \geq 2^t d_1 > K$ and therefore, M is almost $[K]$ -good.

We note here that we can get the bound $\Omega(\sqrt{k}(\log \log k) \log n / \log^2 k)$ by choosing $k_1 = \text{lcm}(1, 2, 3, \dots, m_i) \leq k$, and then $k_i = d'_{i-1} \text{lcm}(1, 2, 3, \dots, m_i) < k$ where $m_i = O(\log(k))$. See [20].

We now give the full proof. We start with some preliminary results, Lemmas 13-18.

Lemma 13. *Let $W \subseteq [m]$ and $w = \gcd(W)$. There is a subset $W' \subseteq W$ of size*

$$O\left(\frac{\log \frac{m}{w}}{\log \log \frac{m}{w}}\right) < \log \frac{m}{w}$$

such that $\gcd(W') = \gcd(W)$.

Proof. Define the set $D = W/w = \{b/w | b \in W\}$. Then $D \subseteq \llbracket m/w \rrbracket$ and $\gcd(D) = 1$. Let $D' \subseteq D$ be a minimum size set with $\gcd(D') = 1$ and $W' = wD' \subseteq W$. Let $D' = \{d_1, \dots, d_t\}$ and $g_i = \gcd(D' \setminus \{d_i\})$ for $i = 1, \dots, t$. Since D' is minimum $g_i > 1$. We also have for $i \neq j$,

$$1 = \gcd(D') = \gcd(\gcd(D' \setminus \{d_i\}), \gcd(D' \setminus \{d_j\})) = \gcd(g_i, g_j)$$

and therefore g_1, \dots, g_t are pairwise relatively prime. Since for all $i > 1$, $g_i = \gcd(D' \setminus \{d_i\}) | d_1$ we have $\prod_{i=2}^t g_i | d_1$. Therefore, $\lfloor m/w \rfloor \geq d_1 \geq \prod_{i=2}^t g_i \geq \prod_{i=2}^t i = t! = |D'|! = |W'|!$ and the result follows. \square

Lemma 14. *Let $d, d', k, y \geq 1$ be integers that satisfy $d|y, d|k, d|d'$ and $\gcd(y, d') = d$. There is $0 \leq \lambda < d'/d$ such that $d'|(k - \lambda y)$.*

Proof. Let $\hat{y} = y/d$, $\hat{k} = k/d$ and $\hat{d} = d'/d$. Then $\gcd(\hat{y}, \hat{d}) = 1$. Consider the set $B = \{\hat{k} - i\hat{y} \mid i = 0, \dots, \hat{d} - 1\}$. If for $0 \leq i_1 < i_2 \leq \hat{d} - 1$ we have $\hat{k} - i_1\hat{y} = (\hat{k} - i_2\hat{y} \pmod{\hat{d}})$ then $(i_1 - i_2)\hat{y} = (0 \pmod{\hat{d}})$. Since $\gcd(\hat{y}, \hat{d}) = 1$ we get $i_1 = (i_2 \pmod{\hat{d}})$ and therefore $i_1 = i_2$. This shows that the elements in B are distinct modulo \hat{d} and therefore there is $0 \leq \lambda < \hat{d} = d'/d$ such that $\hat{k} - \lambda\hat{y} = (0 \pmod{\hat{d}})$. Then $k - \lambda y = (0 \pmod{d'})$. \square

Lemma 15. *Let k be an integer. Let $J = \{j_1, \dots, j_\ell\}$ be a set of integers such that $1 \leq j_1, \dots, j_\ell \leq \sqrt{k}/\ell$ and $d := \gcd(j_1, \dots, j_\ell) \mid k$. There exist non-negative integers $0 \leq \lambda_1, \dots, \lambda_{\ell-1} \leq \sqrt{k}$ and $0 \leq \lambda_\ell \leq k$ such that*

$$\lambda_1 j_1 + \lambda_2 j_2 + \dots + \lambda_\ell j_\ell = k.$$

Proof. We prove the result by induction on ℓ . For $\ell = 1$, given $J = \{j_1\}$, $1 \leq j_1 \leq \sqrt{k}$ and $d = j_1 \mid k$ we let $\lambda_1 = k/d$. Then $\lambda_1 \leq k$ and $\lambda_1 j_1 = k$.

Assume that the result is true for $\ell - 1$. We prove the result for ℓ .

Given $d := \gcd(j_1, \dots, j_\ell) \mid k$. Let $d' = \gcd(j_2, \dots, j_\ell)$. We have two cases: $d' = d$ and $d' > d$. If $d' = d$ then $d' \mid k$ and for $i > 1$, $j_i \leq \sqrt{k}/\ell \leq \sqrt{k}/(\ell - 1)$. By the induction hypothesis there are $0 \leq \lambda_2, \dots, \lambda_{\ell-1} \leq \sqrt{k}$ and $0 \leq \lambda_\ell \leq k$ such that $\lambda_2 j_2 + \lambda_3 j_3 + \dots + \lambda_\ell j_\ell = k$. We choose $\lambda_1 = 0$ and the result follows.

Now suppose $d' > d$. We have $d \mid j_1$, $d \mid k$, $d \mid d'$ and $\gcd(j_1, d') = d$. By Lemma 14, there is λ_1 such that $0 \leq \lambda_1 < d'/d$ and $d' \mid k' := k - \lambda_1 j_1$. Since $\lambda_1 < d'/d \leq j_2 \leq \sqrt{k}$, we also have

$$k' = k - \lambda_1 j_1 \geq k - \sqrt{k} \sqrt{k}/\ell = \frac{\ell - 1}{\ell} k$$

and therefore $j_2, \dots, j_\ell \leq \sqrt{k}/\ell \leq \sqrt{k'}/(\ell - 1)$. Since $d' \mid k'$, by the induction hypothesis there exist $0 \leq \lambda_2, \dots, \lambda_{\ell-1} \leq \sqrt{k'} \leq \sqrt{k}$ and $0 \leq \lambda_\ell \leq k' < k$ such that $\lambda_2 j_2 + \lambda_3 j_3 + \dots + \lambda_\ell j_\ell = k'$. Then $\lambda_1 j_1 + \lambda_2 j_2 + \dots + \lambda_\ell j_\ell = k$. \square

Let M be a $q \times n$ binary matrix. Recall that M_i is the i th column of M . For every $j \geq 1$, let $\ell_j(M)$ denotes the maximum number of disjoint j -subsets A_1, A_2, \dots of $[n]$ such that $\sum_{j \in A_i} M_j = 0$ for all i . We say that M is (j, ℓ) -good if $\ell_j(M) \leq \ell$ and (j, ℓ) -bad if it is not (j, ℓ) -good, i.e., $\ell_j(M) > \ell$. For $L, J \subseteq [n]$, we say that M is (L, ℓ) -good if it is (j, ℓ) -good for all $j \in L$ and (J, ℓ) -bad if it is (g, ℓ) -bad for all $j \in J$. When $\ell = 0$ we just say j -good, L -good, j -bad and J -bad.

For two $q_1 \times n$ and $q_2 \times n$ matrices M and M' , respectively, the *concatenation of M and M'* is $M \circ M' = [M^* \mid M'^*]^*$ where $*$ is the transpose of a matrix. That is, $M \circ M'$ is the $(q_1 + q_2) \times n$ matrix that results from the rows of M follows by the rows of M' .

The following result is obvious

Lemma 16. *If M is (L, ℓ) -good and M' is (L', ℓ) -good then $M \circ M'$ is $(L \cup L', \ell)$ -good.*

Lemma 17. *Let M be a $q \times n$ matrix. If M is $([d], \ell)$ -good then $q = \Omega(d \log((n - (\ell d^2/2))/d))$.*

Proof. For every $j \in [d]$ we have $\ell_j(M) \leq \ell$. That is, for every j , there are at most ℓ disjoint j -sets of columns that sum to zero. We remove those columns (for all $j \in [d]$) and get a $([d], 0)$ -good matrix. The number of columns that are removed is at most $\sum_{j=1}^d \ell j \leq \ell d^2/2$. Using Hamming's bound, Lemma 10, the result follows. \square

We now prove

Lemma 18. *Let m, q, w and $t = mqw$ be integers. Let $J = \{j_1, \dots, j_w\} \subseteq [m]$. Let M be a (J, t) -bad matrix. Then for any $\lambda_1, \dots, \lambda_w \in [q]$ we have that M is $(\lambda_1 j_1 + \dots + \lambda_w j_w)$ -bad.*

Proof. Let $r = \lambda_1 j_1 + \dots + \lambda_w j_w$. We need to show that there are r columns of M that sum to 0. Since M is (j_1, t) -bad and $\lambda_1 \leq t$, there are λ_1 pairwise disjoint j_1 -sets $A_{1,1}, A_{1,2}, \dots, A_{1,\lambda_1}$ such that $\sum_{j \in A_{1,i}} M_j = 0$ for all $i \in [\lambda_1]$. Since M is (j_2, t) -bad and $\lambda_2 \leq t - \lambda_1 j_1$, there are λ_2 pairwise disjoint j_2 -sets $A_{2,1}, A_{2,2}, \dots, A_{2,\lambda_2}$ sets that are also pairwise disjoint with $A_{1,1}, A_{1,2}, \dots, A_{1,\lambda_1}$ such that $\sum_{j \in A_{2,i}} M_j = 0$ for all $i \in [\lambda_2]$. We continue with this procedure until we find a collection \mathcal{A}' of disjoint sets that contains, for every $i \leq w - 1$, λ_i j_i -sets that corresponds to columns of M that sum to 0. Now since $\lambda_w \leq t - (\lambda_1 j_1 + \dots + \lambda_{w-1} j_{w-1})$, there are λ_w pairwise disjoint j_w -sets $A_{w,1}, A_{w,2}, \dots, A_{w,\lambda_w}$ sets that are also pairwise disjoint with all the sets in \mathcal{A}' such that $\sum_{j \in A_{w,i}} M_j = 0$ for all $i \in [\lambda_w]$. Let $\mathcal{A} = \mathcal{A}' \cup \{A_{w,i} | i \in [\lambda_w]\}$. Obviously, $|\cup \mathcal{A}| = \lambda_1 j_1 + \dots + \lambda_w j_w$ and $\sum_{j \in \cup \mathcal{A}} M_j = 0$. \square

We now show that if a k -good matrix M is $(J, \text{poly}(k))$ -bad then $\gcd(J) \nmid k$.

Lemma 19. *Let $K = \lfloor \sqrt{k}/(2 \log k) \rfloor$, $\kappa = k^{1.5}$, $J \subseteq [K]$ and $k/2 \leq k' \leq k$. Let M be a matrix that is k' -good and (J, κ) -bad. Then $\gcd(J) \nmid k'$.*

Proof. Let $d = \gcd(J)$ and suppose, for the contrary, that $d | k'$. By Lemma 13, there is $J' \subseteq J$ of size $w := |J'| \leq \log(K/d) < \log k$ such that $d = \gcd(J')$. Let $J' = \{j_1, \dots, j_w\}$. By Lemma 15, there exist $0 \leq \lambda_1, \dots, \lambda_w \leq k$ such that $\lambda_1 j_1 + \dots + \lambda_w j_w = k'$. By Lemma 18, M is k' -bad. A contradiction. \square

Let $K = \lfloor \sqrt{k}/(2 \log k) \rfloor$ and $\kappa = k^{1.5}$. Let \mathbb{N}_d be the set of integers in $[K]$ that are not divisible by d .

Lemma 20. *Let J be the maximum subset of $[K]$ such that M is (J, κ) -bad. Then M is $(\mathbb{N}_{\gcd(J)}, \kappa)$ -good.*

Proof. Since J is the maximum set, M is $([K] \setminus J, \kappa)$ -good. Since $J \subseteq [K] \setminus \mathbb{N}_{\gcd(J)}$ we have $[K] \setminus J \supseteq \mathbb{N}_{\gcd(J)}$ and therefore M is $(\mathbb{N}_{\gcd(J)}, \kappa)$ -good. \square

We now show how to construct from a (\mathbb{N}_d, κ) -good matrix a $(\mathbb{N}_{d'}, \kappa)$ -good matrix with $d' \geq 2d$.

Lemma 21. *Let M be a $q \times n$ matrix that is (\mathbb{N}_d, κ) -good. There exist $k' \leq k$, $q' = q + \Pi(k', n)$, $d' \geq 2d$ and a $q' \times n$ matrix M' that is $(\mathbb{N}_{d'}, \kappa)$ -good.*

Proof. Consider $k' = d \lfloor k/d \rfloor$ and let \hat{M} be a $\Pi(n, k') \times n$ matrix that is k' -good. Let J' be the maximum subset of $[K]$ such that \hat{M} is (J', κ) -bad. By Lemma 19, $\gcd(J') \nmid k' = d \lfloor k/d \rfloor$ and therefore $\gcd(J') \nmid d$. By Lemma 20, \hat{M} is $(\mathbb{N}_{\gcd(J')}, \kappa)$ -good. Define $M' = M \circ \hat{M}$.

First, the number of rows of M' is $q' = q + \Pi(k', n)$. Now, by Lemma 16, M' is $(\mathbb{N}_{\gcd(J') \cup \mathbb{N}_d}, \kappa)$ -good. Since $\mathbb{N}_{\gcd(J')} \cup \mathbb{N}_d = \mathbb{N}_{d'}$ for $d' = \text{lcm}(\gcd(J'), d)$ we have that M' is $(\mathbb{N}_{d'}, \kappa)$ -good. Since $\gcd(J') \nmid d$ we have $d' = \text{lcm}(\gcd(J'), d) \geq 2d$. This implies the result. \square

We are ready now to prove the final result

Lemma 22. *For $n \geq k^{2.5}$ there is $k' \leq k$ such that $\Pi(n, k') = \Omega((\sqrt{k}/\log^2 k) \log n)$.*

Proof. Let M be the $1 \times n$ matrix $[111 \cdots 1]$. Then M is \mathbb{N}_2 -good. By Lemma 21, there exist $k_1, k_2, \dots, k_t \leq k$, $t = O(\log k)$, $q_t = 1 + \Pi(k_1, n) + \dots + \Pi(k_t, n)$, $d' \geq 2^{t+1} > K$ and a $q_t \times n$ matrix M' that is $(\mathbb{N}_{d'}, \kappa)$ -good. Since $d' > K$, M' is $([K], \kappa)$ -good. By Lemma 17,

$$q_t = \Omega \left(K \log \frac{n - \kappa K^2}{K} \right) = \Omega \left(\frac{\sqrt{k}}{\log k} \log n \right).$$

Therefore, there exists $k' := k_i \leq k$ such that

$$\Pi(n, k') = \Omega \left(\frac{\sqrt{k}}{\log^2 k} \log n \right).$$

□

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